OPEN **Publisher Correction:** Upper critical field and superconductor-metal transition in ultrathin niobium films

Iryna Zaytseva, Aleksander Abaloszew, Bruno C. Camargo, Yevgen Syryanyy & Marta Z. Cieplak

Correction to: *Scientific Reports* <https://doi.org/10.1038/s41598-020-75968-9>, published online 04 November 2020

This Article contains an error in Figure 1 where all data points in the right inset of panel (g) are missing.

The correct Figure 1 appears below.

Published online: 13 April 2021

Figure 1. R_{sq} versus T for various B as labeled near the curves (in teslas) (a–d), and R_{sq} versus B at various T as labeled near the curves (e–g), for films with various d : (a) 9.5 nm, (b) 3.9 nm, (c) 1.4 nm, (d) 1.2 nm, (e) 9.5 nm, (f) 1.4 nm, (g) 1.2 nm. Red arrows indicate B_c . Insets in (c) and (d): regions of negative MR on the expanded scale. Inset in (e): expanded region near B_c . Inset in (f): B_c versus G_c (measured at the lowest T). Blue curve shows the fit described in the text, $B_c = A(G_c - G_{c0})^p$. Right inset in (g): B_c versus T for several amorphous films. The arrows indicate T_0 , below which B_c is constant. Left inset in (g): B_c and T_0 versus $G_c - G_{c0}$ on a double logarithmic scale. The lines have slopes of 0.6 and 0.24, respectively.

Open Access This article is licensed under a Creative Commons Attribution 4.0 International License, which permits use, sharing, adaptation, distribution and reproduction in any medium or format, as long as you give appropriate credit to the original author(s) and the source, provide a link to the Creative Commons licence, and indicate if changes were made. The images or other third party material in this article are included in the article's Creative Commons licence, unless indicated otherwise in a credit line to the material. If material is not included in the article's Creative Commons licence and your intended use is not permitted by statutory regulation or exceeds the permitted use, you will need to obtain permission directly from the copyright holder. To view a copy of this licence, visit <http://creativecommons.org/licenses/by/4.0/>.

© The Author(s) 2021